

# Resource Summary Report

Generated by NIF on Sep 15, 2026

## FEI: Meridian V System for Semiconductors

RRID:SCR\_019889

Type: Tool

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### Proper Citation

FEI: Meridian V System for Semiconductors (RRID:SCR\_019889)

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### Resource Information

**URL:** <https://www.fei.com/products/efa/meridian-v-for-semiconductors/>

**Proper Citation:** FEI: Meridian V System for Semiconductors (RRID:SCR\_019889)

**Description:** Electrical failure analysis system for semiconductors with optimized dynamic LSM platform that supports automated test equipment docking and back side analysis with laser voltage probing, laser voltage imaging, and laser simulation for critical path analysis.

**Resource Type:** instrument resource

**Keywords:** FEI, EFA System, Instrument Equipment, USEDit,

**Availability:** Commercially available

**Resource Name:** FEI: Meridian V System for Semiconductors

**Resource ID:** SCR\_019889

**Alternate IDs:** Model\_Number\_Meridian\_V

**Record Creation Time:** 20220129T080347+0000

**Record Last Update:** 20260912T195924+0000

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### Ratings and Alerts

No rating or validation information has been found for FEI: Meridian V System for Semiconductors.

No alerts have been found for FEI: Meridian V System for Semiconductors.

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### Data and Source Information

**Source:** [SciCrunch Registry](#)

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## Usage and Citation Metrics

We have not found any literature mentions for this resource.